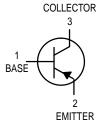
# **General Purpose Transistors**

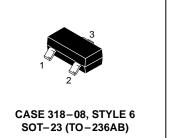
PNP Silicon



#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector–Emitter Voltage	VCEO	-32	Vdc
Collector-Base Voltage	VCBO	-32	Vdc
Emitter–Base Voltage	V <sub>EBO</sub>	-5.0	Vdc
Collector Current – Continuous	lс	-100	mAdc

## BCW29LT1 BCW30LT1



#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Dissipation FR-5 Board (1)  TA = 25°C	PD	225	mW
Derate above 25°C		1.8	mW/°C
Thermal Resistance, Junction to Ambient	$R_{ heta JA}$	556	°C/W
Total Device Dissipation Alumina Substrate, (2) T <sub>A</sub> = 25°C	P <sub>D</sub>	300	mW
Derate above 25°C		2.4	mW/°C
Thermal Resistance, Junction to Ambient	$R_{ heta JA}$	417	°C/W
Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C

#### **DEVICE MARKING**

BCW29LT1 = C1; BCW30LT1 = C2

#### **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector–Emitter Breakdown Voltage (I <sub>C</sub> = -2.0 mAdc, I <sub>E</sub> = 0)	V(BR)CEO	-32	_	Vdc
Collector–Emitter Breakdown Voltage (I <sub>C</sub> = –100 μAdc, V <sub>EB</sub> = 0)	V(BR)CES	-32	_	Vdc
Collector–Base Breakdown Voltage (IC = $-10 \mu$ Adc, IC = $0$ )	V(BR)CBO	-32	_	Vdc
Emitter–Base Breakdown Voltage ( $I_E = -10 \mu Adc$ , $I_C = 0$ )	V(BR)EBO	-5.0	_	Vdc
Collector Cutoff Current (V <sub>CB</sub> = -32 Vdc, I <sub>E</sub> = 0) (V <sub>CB</sub> = -32 Vdc, I <sub>E</sub> = 0, T <sub>A</sub> = 100°C)	ICBO	_ _	-100 -10	nAdc μAdc

<sup>1.</sup> FR-5 =  $1.0 \times 0.75 \times 0.062$  in.

Thermal Clad is a trademark of the Bergquist Company



<sup>2.</sup> Alumina =  $0.4 \times 0.3 \times 0.024$  in. 99.5% alumina.

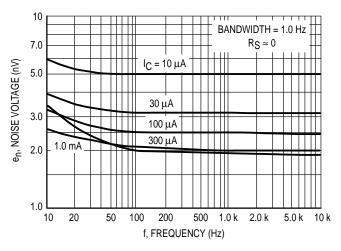
#### **BCW29LT1 BCW30LT1**

### **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise noted)

Characteristic		Min	Max	Unit
ON CHARACTERISTICS	•	•		
DC Current Gain ( $I_C = -2.0 \text{ mAdc}$ , $V_{CE} = -5.0 \text{ Vdc}$ ) BCW2 BCW3	·	120 215	260 500	_ _
Collector–Emitter Saturation Voltage (I <sub>C</sub> = -10 mAdc, I <sub>B</sub> = -0.5 mAdc)	VCE(sat)	_	-0.3	Vdc
Base–Emitter On Voltage ( $I_C = -2.0 \text{ mAdc}$ , $V_{CE} = -5.0 \text{ Vdc}$ )	V <sub>BE</sub> (on)	-0.6	-0.75	Vdc
SMALL-SIGNAL CHARACTERISTICS	-			
Output Capacitance (IE = 0, V <sub>CB</sub> = -10 Vdc, f = 1.0 MHz)	C <sub>obo</sub>	_	7.0	pF
Noise Figure (I <sub>C</sub> = $-0.2$ mAdc, V <sub>CE</sub> = $-5.0$ Vdc, R <sub>S</sub> = $2.0$ k $\Omega$ , f = $1.0$ kHz, BW = $200$ Hz)	NF	_	10	dB

#### TYPICAL NOISE CHARACTERISTICS

 $(V_{CE} = -5.0 \text{ Vdc}, T_A = 25^{\circ}C)$ 



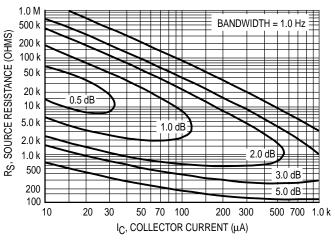
1.0 7.0 BANDWIDTH = 1.0 Hz 5.0 R<sub>S</sub> ≈ ∞  $I_C = 1.0 \text{ mA}$ In, NOISE CURRENT (pA) 3.0 2.0 300 μΑ 1.0 0.7 100 μΑ 0.5 0.3 30 μΑ 0.2 10 μA 0.1 20 200 1.0 k 2.0 k 50 100 500 5.0 k 10 10 k f, FREQUENCY (Hz)

Figure 1. Noise Voltage

Figure 2. Noise Current

#### **NOISE FIGURE CONTOURS**

 $(V_{CE} = -5.0 \text{ Vdc}, T_{A} = 25^{\circ}\text{C})$ 



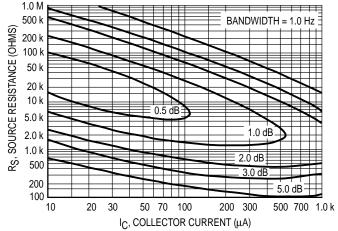


Figure 3. Narrow Band, 100 Hz

Figure 4. Narrow Band, 1.0 kHz

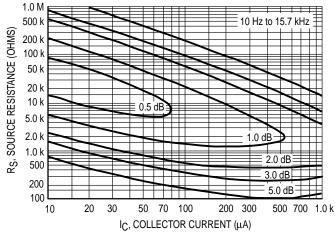


Figure 5. Wideband

Noise Figure is Defined as:

NF = 20 
$$\log_{10} \left[ \frac{e_n^2 + 4KTR_S + I_n^2 R_S^2}{4KTR_S} \right]^{1/2}$$

 $e_n$  = Noise Voltage of the Transistor referred to the input. (Figure 3)

In = Noise Current of the Transistor referred to the input. (Figure 4)

 $K = Boltzman's Constant (1.38 x 10^{-23} j/{}^{\circ}K)$ 

T = Temperature of the Source Resistance (°K)

Rs = Source Resistance (Ohms)

#### TYPICAL STATIC CHARACTERISTICS

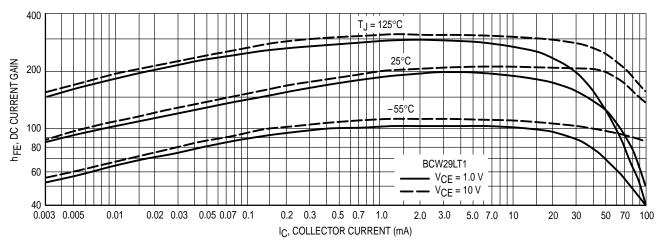


Figure 6. DC Current Gain

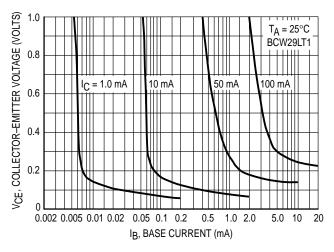


Figure 7. Collector Saturation Region

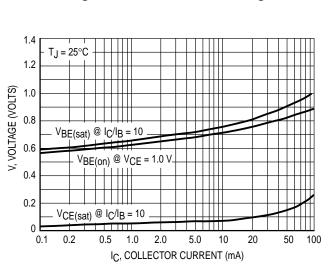


Figure 9. "On" Voltages

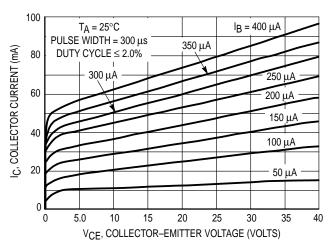
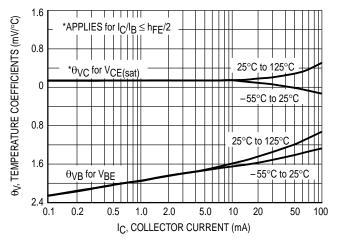


Figure 8. Collector Characteristics



**Figure 10. Temperature Coefficients** 

#### TYPICAL DYNAMIC CHARACTERISTICS

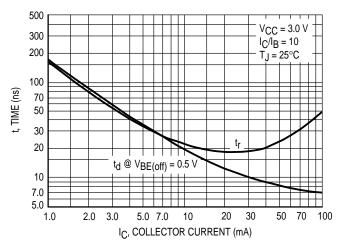


Figure 11. Turn-On Time

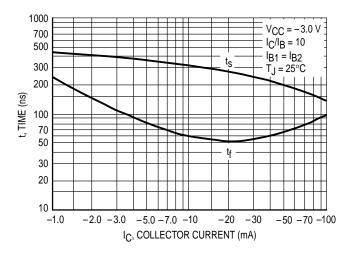


Figure 12. Turn-Off Time

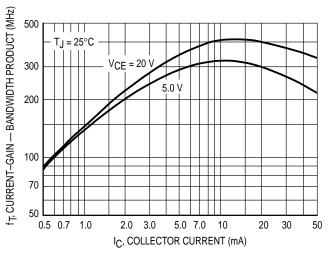


Figure 13. Current-Gain — Bandwidth Product

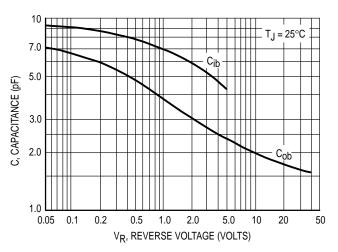


Figure 14. Capacitance

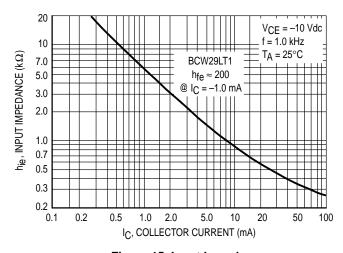


Figure 15. Input Impedance

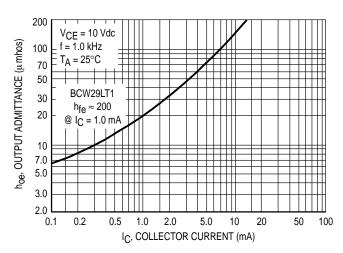


Figure 16. Output Admittance

#### **BCW29LT1 BCW30LT1**

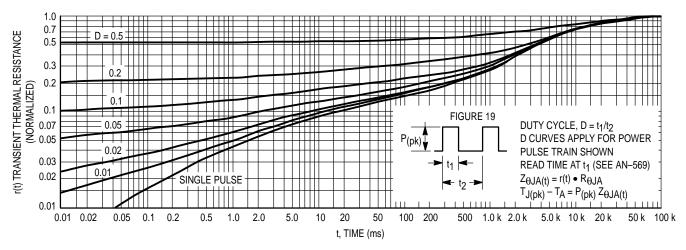


Figure 17. Thermal Response

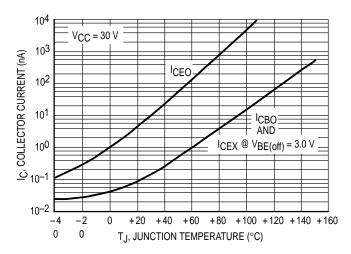


Figure 18. Typical Collector Leakage Current

#### **DESIGN NOTE: USE OF THERMAL RESPONSE DATA**

A train of periodical power pulses can be represented by the model as shown in Figure 19. Using the model and the device thermal response the normalized effective transient thermal resistance of Figure 17 was calculated for various duty cycles.

To find  $Z_{\theta JA(t)},$  multiply the value obtained from Figure 17 by the steady state value  $R_{\theta JA}.$ 

#### Example:

The BCW29LT1 is dissipating 2.0 watts peak under the following conditions:

$$t_1 = 1.0 \text{ ms}, t_2 = 5.0 \text{ ms} (D = 0.2)$$

Using Figure 17 at a pulse width of 1.0 ms and D = 0.2, the reading of r(t) is 0.22.

The peak rise in junction temperature is therefore

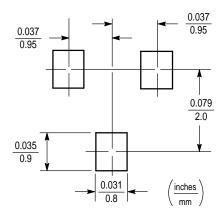
 $\Delta T = r(t) \times P_{(pk)} \times R_{\theta JA} = 0.22 \times 2.0 \times 200 = 88^{\circ}C.$ 

For more information, see AN-569.

#### INFORMATION FOR USING THE SOT-23 SURFACE MOUNT PACKAGE

#### MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



SOT-23

#### SOT-23 POWER DISSIPATION

The power dissipation of the SOT–23 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet for the SOT–23 package,  $P_D$  can be calculated as follows:

$$P_D = \frac{T_{J(max)} - T_A}{R_{\theta,JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of  $25^{\circ}C$ , one can calculate the power dissipation of the device which in this case is 225 milliwatts.

$$P_D = \frac{150^{\circ}C - 25^{\circ}C}{556^{\circ}C/W} = 225 \text{ milliwatts}$$

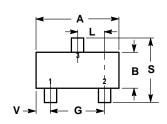
The 556°C/W for the SOT–23 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 225 milliwatts. There are other alternatives to achieving higher power dissipation from the SOT–23 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad™. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

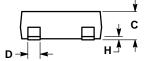
#### **SOLDERING PRECAUTIONS**

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.\*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes.
   Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.
- \* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

#### PACKAGE DIMENSIONS







**CASE 318-08 ISSUE AE** SOT-23 (TO-236AB)

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH.
  MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.1102	0.1197	2.80	3.04	
В	0.0472	0.0551	1.20	1.40	
С	0.0350	0.0440	0.89	1.11	
D	0.0150	0.0200	0.37	0.50	
G	0.0701	0.0807	1.78	2.04	
Н	0.0005	0.0040	0.013	0.100	
J	0.0034	0.0070	0.085	0.177	
K	0.0180	0.0236	0.45	0.60	
L	0.0350	0.0401	0.89	1.02	
S	0.0830	0.0984	2.10	2.50	
٧	0.0177	0.0236	0.45	0.60	

STYLE 6:

PIN 1. BASE 2. EMITTER

COLLECTOR

Motorola reserves the right to make changes without further notice to any products herein. Motorola makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Motorola assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters which may be provided in Motorola data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. Motorola does not convey any license under its patent rights nor the rights of others. Motorola products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Motorola product could create a situation where personal injury  $or death\,may\,occur.\,Should\,Buyer\,pur chase\,or\,use\,Motorola\,products\,for\,any\,such\,unintended\,or\,unauthorized\,application,\,Buyer\,shall\,indemnify\,and\,hold\,Motorola\,pure,\,Anderson,\,Anderso$ and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Motorola was negligent regarding the design or manufacture of the part. Motorola and 祸 are registered trademarks of Motorola, Inc. Motorola, Inc. is an Equal Opportunity/Affirmative Action Employer.

#### How to reach us:

USA/EUROPE/Locations Not Listed: Motorola Literature Distribution; P.O. Box 20912; Phoenix, Arizona 85036. 1-800-441-2447 or 602-303-5454

MFAX: RMFAX0@email.sps.mot.com - TOUCHTONE 602-244-6609 INTERNET: http://Design-NET.com

JAPAN: Nippon Motorola Ltd.; Tatsumi-SPD-JLDC, 6F Seibu-Butsuryu-Center, 3-14-2 Tatsumi Koto-Ku, Tokyo 135, Japan. 03-81-3521-8315

ASIA/PACIFIC: Motorola Semiconductors H.K. Ltd.; 8B Tai Ping Industrial Park, 51 Ting Kok Road, Tai Po, N.T., Hong Kong. 852-26629298

